

High Temperature, Low Voltage 8-Channel Multiplexer

Data Sheet ADG798

FEATURES

Extreme high temperature operation up to 210°C 3.0 V to 5.5 V single supply ± 2.5 V dual supply 10 Ω on resistance, maximum 2 Ω on-resistance flatness, maximum 12 ns switching times Single 8:1 multiplexer Low power consumption TTL-/CMOS-compatible inputs

APPLICATIONS

Downhole drilling and instrumentation Avionics Heavy industrial High temperature environments

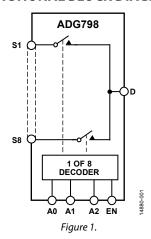
GENERAL DESCRIPTION

The ADG798 is a low voltage, CMOS, analog multiplexer designed to operate at very high temperatures up to 210°C. The ADG798 switches one of eight inputs (S1 to S8) to a common output, D, as determined by the 3-bit binary address lines A0, A1, and A2. An EN input on the device enables or disables the device. When the device is disabled, all channels are switched off.

The ADG798 features low power consumption and a 3.3 V to 5.5 V operating supply range. All channels exhibit break-before-make switching action, preventing momentary shorting when switching channels. These switches are designed with an enhanced submicron process that provides low power dissipation, high switching speed, and very low on resistance.

The on resistance ($R_{\rm ON}$) is a maximum of 10 Ω and is closely matched between switches and very flat over the full signal range. The ADG798 operates equally well as either a multiplexer or a demultiplexer and has an input signal range that extends to the supplies.

FUNCTIONAL BLOCK DIAGRAM



This mux is available in a 16-lead ceramic flat package (FLATPACK) and a 16-lead ceramic flat package with reverse formed gullwing leads (FLATPACK_RF). Both packages have an operating temperature range of –55°C to +210°C, are designed for robustness at extreme temperatures, and are qualified for 1000 hours of continuous operation at the maximum temperature rating.

The ADG798 is a member of a growing series of high temperature qualified products offered by Analog Devices, Inc. For a complete selection table of available high temperature products, see the high temperature product list and qualification data available at http://www.analog.com/hightemp.

PRODUCT HIGHLIGHTS

- 1. Single-Supply/Dual-Supply Operation. The ADG798 is fully specified and guaranteed with 3.3 V and 5 V single-supply rails and ± 2.5 V dual-supply rails.
- 2. Low Ron. The Ron of the ADG798 is specified at 5 Ω , typical, at 210°C.
- 3. Low Power Consumption. The power consumption of the ADG798 is specified at $<\!0.01~\mu W.$
- 4. Guaranteed Break-Before-Make Switching Action.

ADG798* PRODUCT PAGE QUICK LINKS

Last Content Update: 02/23/2017

COMPARABLE PARTS 🖵

View a parametric search of comparable parts.

EVALUATION KITS

· ADG798 Evaluation Board

DOCUMENTATION

Data Sheet

 ADG798: High Temperature, Low Voltage 8-Channel Multiplexer Data Sheet

User Guides

 UG-1039: Evaluation Board for the ADG798 High Temperature, Low Voltage, 8-Channel Multiplexer

DESIGN RESOURCES

- · ADG798 Material Declaration
- PCN-PDN Information
- · Quality And Reliability
- Symbols and Footprints

DISCUSSIONS

View all ADG798 EngineerZone Discussions.

SAMPLE AND BUY 🖵

Visit the product page to see pricing options.

TECHNICAL SUPPORT 🖳

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REVISION HISTORY

9/2016—Revision 0: Initial Version

SPECIFICATIONS

 $V_{DD} = 5~V~\pm~10\%, V_{SS} = 0~V, GND = 0~V, -55^{\circ}C \leq T_{A} \leq +210^{\circ}C, unless~otherwise~noted.$

Table 1.

Parameter	Symbol	Test Conditions/Comments ¹	Min	Typ ²	Max	Unit
ANALOG SWITCH						
Analog Signal Range			0 V		V_{DD}	V
On Resistance	R _{ON}	$V_S = 0 \text{ V to } V_{DD}$, $I_{DS} = 10 \text{ mA}$; see Figure 24		5	10	Ω
Matching Between Channels	ΔR_{ON}	$V_S = 0 \text{ V to } V_{DD}, I_{DS} = 10 \text{ mA}$		1.25	1.5	Ω
Flatness	R _{FLAT (ON)}	$V_S = 0 \text{ V to } V_{DD}$, $I_{DS} = 10 \text{ mA}$		0.75	2	Ω
LEAKAGE CURRENTS		$V_{DD} = 5.5 \text{ V}$				
Source Off Leakage	Is (Off)	$V_D = 4.5 \text{ V/1 V}, V_S = 1 \text{ V/4.5 V}; \text{ see Figure 25}$	-180	±0.01	+180	nA
Drain Off Leakage	I _D (Off)	$V_D = 4.5 \text{ V/1 V}, V_S = 1 \text{ V/4.5 V}; \text{ see Figure 26}$	-2600	±0.01	+2600	nA
Channel On Leakage	I_D , I_S (On)	$V_D = V_S = 1 \text{ V or } 4.5 \text{ V}$; see Figure 27	-2600	±0.01	+2600	nA
DIGITAL INPUTS						
Input Voltage						
High	V _{INH}		2.4			V
Low	V _{INL}				0.8	V
Input Current	I _{INL} or I _{INH}	$V_{IN} = V_{INL}$ or V_{INH}	-800	+0.005	+800	nA
Digital Input Capacitance	CIN			2		рF
DYNAMIC CHARACTERISTICS ³						
Transition Time	ttransition	$R_L = 150 \Omega$, $C_L = 15 pF$; see Figure 28		12	23	ns
		$V_{S1} = 3 \text{ V/0 V}, V_{S8} = 0 \text{ V/3 V}$				
Break-Before-Make Time Delay	topen	$R_L = 150 \Omega$, $C_L = 15 pF$, $V_S = 3 V$; see Figure 29	1	8		ns
		T _A = 210°C		9		ns
On Time	ton (EN)	$R_L = 150 \Omega$, $C_L = 15 pF$		11	20	ns
		$V_s = 3 \text{ V}$; see Figure 30				
Off Time	t _{OFF} (EN)	$R_L = 150 \Omega, C_L = 15 pF$		5.5	12	ns
		$V_S = 3 V$; see Figure 30				
Charge Injection	Qını	$V_S = 2.5 \text{ V}$, $R_S = 0 \Omega$, $C_L = 1 \text{ nF}$; See Figure 31		±3		рС
Off Isolation		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$		-60		dB
		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 32		-80		dB
Channel to Channel Crosstalk		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$		-60		dB
		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 33		-80		dB
–3 dB Bandwidth		$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 34		55		MHz
Source Capacitance, Off	Cs (Off)	f = 1 MHz		13		рF
Drain Capacitance, Off	C _D (Off)	f = 1 MHz		85		pF
Source/Drain Capacitance, On	C _D , C _S (On)	f = 1 MHz		96		pF
POWER REQUIREMENTS		$V_{DD} = 5.5 \text{ V}$				
Supply Current	I _{DD}	Digital inputs = 0 V or 5.5 V		40	70	μΑ

 $^{^1}$ The ADG798 is qualified for a minimum of 1000 hours of continuous operation at the maximum temperature rating. 2 T_A = 25°C, except for the analog switch and power requirements values where T_A = 210°C. 3 Guaranteed by design, not subject to production test.

 $V_{DD} = 3.3 \text{ V} \pm 10\%$, $V_{SS} = 0 \text{ V}$, GND = 0 V, $-55^{\circ}C \le T_{A} \le +210^{\circ}C$, unless otherwise noted.

Parameter	Symbol	Test Conditions/Comments ¹	Min	Typ²	Max	Unit
ANALOG SWITCH						
Analog Signal Range			0 V		V_{DD}	V
On Resistance	Ron	$V_S = 0 \text{ V to } V_{DD}$, $I_{DS} = 10 \text{ mA}$; see Figure 24		8	20	Ω
Matching Between Channels	ΔR_{ON}	$V_S = 0 \text{ V to } V_{DD}, I_{DS} = 10 \text{ mA}$		0.5	1.5	Ω
Flatness	R _{FLAT} (ON)	$V_S = 0 \text{ V to } V_{DD}$, $I_{DS} = 10 \text{ mA}$		3	4.5	Ω
LEAKAGE CURRENTS		$V_{DD} = 3.63 \text{ V}$				
Source Off Leakage	Is (Off)	$V_D = 2.3 \text{ V/1 V}, V_S = 1 \text{ V/2.3 V}; \text{ see Figure 25}$	-180	±0.01	+180	nA
Drain Off Leakage	I _D (Off)	$V_D = 2.3 \text{ V/1 V}, V_S = 1 \text{ V/2.3 V}; \text{ see Figure 26}$	-2600	±0.01	+2600	nA
Channel On Leakage	I _D , I _S (On)	$V_D = V_S = 1 \text{ V or } 2.3 \text{ V}$; see Figure 27	-2600	±0.01	+2600	nA
DIGITAL INPUTS						
Input Voltage						
High	V _{INH}		2.0			V
Low	V _{INL}				8.0	V
Input Current	I _{INL} or I _{INH}	$V_{IN} = V_{INL}$ or V_{INH}	-800	+0.005	+800	nA
Digital Input Capacitance	C _{IN}			2		рF
DYNAMIC CHARACTERISTICS ³						
Transition Time	transition	$R_L = 150 \Omega$, $C_L = 15 pF$; see Figure 28		18	38	ns
		$V_{S1} = 2 \text{ V/O V}, V_{S8} = 0 \text{ V/2 V}$				
Break-Before-Make Time Delay	topen	$R_L = 150 \Omega$, $C_L = 15 pF$, $V_S = 2 V$; see Figure 29	1	10		ns
		T _A = 210°C		15		ns
On Time	ton (EN)	$R_L = 150 \Omega$, $C_L = 15 pF$		14	28	ns
		V _s = 2 V; see Figure 30				
Off Time	t _{OFF} (EN)	$R_L = 150 \Omega$, $C_L = 15 pF$		8.5	17	ns
		V _s = 2 V; see Figure 30				
Charge Injection	Q _{INJ}	$V_S = 1.5 \text{ V}, R_S = 0 \Omega, C_L = 1 \text{ nF}; \text{ see Figure 31}$		±3		рC
Off Isolation		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$		-60		dB
		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 32		-80		dB
Channel to Channel Crosstalk		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$		-60		dB
		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 33		-80		dB
–3 dB Bandwidth		$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 34		55		MHz
Source Capacitance, Off	Cs (Off)	f = 1 MHz		13		pF
Drain Capacitance, Off	C _D (Off)	f = 1 MHz		85		рF
Source/Drain Capacitance, On	C _D , C _s (On)	f=1 MHz		96		pF
POWER REQUIREMENTS		V _{DD} = 3.63 V				
Supply Current	I_{DD}	Digital inputs = 0 V or 3.63 V		40	70	μΑ

 $^{^1}$ The ADG798 is qualified for a minimum of 1000 hours of continuous operation at the maximum temperature rating. 2 T_A = 25°C, except for the analog switch and power requirements values where T_A = 210°C. 3 Guaranteed by design, not subject to production test.

DUAL SUPPLY

 $V_{DD} = 2.5~V \pm 10\%, V_{SS} = -2.5~V \pm 10\%, GND = 0~V, -55^{\circ}C \leq T_{A} \leq +210^{\circ}C, unless~otherwise~noted.$

Table 3.

Parameter	Symbol	Test Conditions/Comments ¹	Min	Typ ²	Max	Unit
ANALOG SWITCH						
Analog Signal Range			Vss		V_{DD}	V
On Resistance	Ron	$V_S = V_{SS}$ to V_{DD} , $I_{DS} = 10$ mA; see Figure 24		5	10	Ω
Matching Between Channels	ΔR_{ON}	$V_S = V_{SS}$ to V_{DD} , $I_{DS} = 10$ mA		1.25	1.5	Ω
Flatness	R _{FLAT (ON)}	$V_S = V_{SS}$ to V_{DD} , $I_{DS} = 10$ mA		0.6	2	Ω
LEAKAGE CURRENTS		$V_{DD} = +2.75 \text{ V}, V_S = -2.75 \text{ V}$				
Source Off Leakage	I _s (Off)	$V_S = +2.25 \text{ V/} -1.25 \text{ V}, V_D = -1.25 \text{ V/} +2.25 \text{ V}; see Figure 25$	-180	±0.01	+180	nA
Drain Off Leakage	I _D (Off)	$V_S = +2.25 \text{ V/} -1.25 \text{ V, } V_D = -1.25 \text{ V/} +2.25 \text{ V; see Figure 26}$	-2600	±0.01	+2600	nA
Channel On Leakage	I _D , I _s (On)	$V_D = V_S = -1.25 \text{ V/+2.25 V}$; see Figure 27	-2600	±0.01	+2600	nA
DIGITAL INPUTS						
Input Voltage						
High	V _{INH}		2.0			V
Low	V _{INL}				0.8	V
Input Current	I _{INL} or I _{INH}	$V_{IN} = V_{INL} \text{ or } V_{INH}$	-800	+0.005	+800	nA
Digital Input Capacitance	C _{IN}			2		pF
DYNAMIC CHARACTERISTICS ³						
Transition Time	t transition	$R_L = 150 \Omega$, $C_L = 15 pF$; see Figure 28 $V_{S1} = 1.5 V/0 V$, $V_{S8} = 0 V/1.5 V$		14	30	ns
Break-Before-Make Time Delay	topen	$R_L = 150 \Omega$, $C_L = 15 pF$, $V_S = 2 V$; see Figure 29	1	10		ns
		T _A = 210°C		13		ns
On Time	ton (EN)	$R_L = 150 \Omega$, $C_L = 15 pF$ $V_S = 2 V$; see Figure 30		19	30	ns
OffTime	t _{OFF} (EN)	$R_L = 150 \Omega$, $C_L = 15 pF$ $V_S = 2 V$; see Figure 30		11.5	20	ns
Charge Injection	Q _{INJ}	$V_S = 0$ V, $R_S = 0$ Ω , $C_L = 1$ nF; see Figure 31		±3		pC
Off Isolation		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$		-60		dB
		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 32		-80		dB
Channel to Channel Crosstalk		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 10 MHz$		-60		dB
		$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 33		-80		dB
–3 dB Bandwidth		$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 34	4 55		MHz	
Source Capacitance, Off	Cs (Off)	f = 1 MHz	13		pF	
Drain Capacitance, Off	C _D (Off)	f = 1 MHz	85		pF	
Source/Drain Capacitance, On	C_D , C_S (On)	f = 1 MHz	96		pF	
POWER REQUIREMENTS		$V_{DD} = 2.75 \text{ V}$				
Supply Current	I _{DD}	Digital inputs = 0 V or 2.75 V		40	70	μΑ
	Iss	$V_{SS} = -2.75 \text{ V}$; digital inputs = 0 V or 2.75 V		40	70	μΑ

 $^{^1}$ The ADG798 is qualified for a minimum of 1000 hours of continuous operation at the maximum temperature rating. 2 T_A = 25°C, except for the analog switch and power requirements values where T_A = 210°C. 3 Guaranteed by design, not subject to production test.

CONTINUOUS CURRENT PER CHANNEL, Sx OR D

Table 4.

Parameter	175°C	210°C	Unit
CONTINUOUS CURRENT, Sx OR D			
$V_{DD} = 5 \text{ V}, V_{SS} = 0 \text{ V}, \theta_{JA} = 70^{\circ}\text{C/W}$	30	30	mA maximum
$V_{DD} = 3 \text{ V, } V_{SS} = 0 \text{ V, } \theta_{JA} = 70^{\circ}\text{C/W}$	30	30	mA maximum
$V_{DD} = +2.5 \text{ V}, V_{SS} = -2.5 \text{ V}, \theta_{JA} = 70^{\circ}\text{C/W}$	30	30	mA maximum

ABSOLUTE MAXIMUM RATINGS

 $T_A = 25$ °C, unless otherwise noted.

Table 5.

1 0010 01	
Parameter	Rating
V _{DD} to V _{SS}	7 V
V _{DD} to GND	-0.3 V to +7 V
V_{SS} to GND	+0.3 V to −3.5 V
Analog Inputs ¹	V _{SS} – 0.3 V to V _{DD} + 0.3 V or 30 mA, whichever occurs first
Digital Inputs ¹	-0.3 V to V _{DD} + 0.3 V or 30 mA, whichever occurs first
Peak Current, Sx or D (Pulsed at 1 ms, 10% Duty Cycle Maximum)	94.9 mA
Continuous Current, Sx or D ²	Data + 5%
Operating Temperature Range	−55°C to +210°C
Junction Temperature	211°C

¹ Overvoltages at Ax, EN, Sx, or D are clamped by internal codes. Limit the current to the maximum ratings given.

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

Only one absolute maximum rating can be applied at any one time.

THERMAL RESISTANCE

Thermal performance is directly linked to PCB design and operating environment. Close attention to PCB thermal design is required.

Table 6. Thermal Resistance

Package Type ¹	θ _{JA}	θ _{JC}	Unit
F-16-1	70	22	°C/W
FR-16-1	70	10	°C/W

¹ Thermal impedance simulated values are based on a JEDEC 2s2p thermal test board. See JEDEC JESD51.

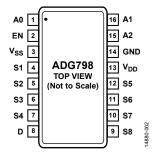
ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

² See Table 4.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



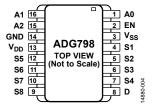


Figure 2. FLATPACK Pin Configuration

Figure 3. Reversed Formed FLATPACK Pin Configuration

Table 7. Pin Function Descriptions

Pin No.	Mnemonic	Description
1	A0	Digital Input. This pin controls the configuration of the switch, as described in the truth table (see Table 8).
2	EN	Digital Input. This pin controls the configuration of the switch, as shown in the truth table (see Table 8).
3	V_{SS}	Most Negative Power Supply Pin in Dual-Supply Applications. For single-supply applications, tie this pin to GND.
4	S1	Source Terminal. This pin can be an input or output.
5	S2	Source Terminal. This pin can be an input or output.
6	S3	Source Terminal. This pin can be an input or output.
7	S4	Source Terminal. This pin can be an input or output.
8	D	Drain Terminal. This pin can be an input or output.
9	S8	Source Terminal. This pin can be an input or output.
10	S7	Source Terminal. This pin can be an input or output.
11	S6	Source Terminal. This pin can be an input or output.
12	S5	Source Terminal. This pin can be an input or output.
13	V_{DD}	Most Positive Power Supply Pin.
14	GND	Ground (0 V) Reference.
15	A2	Digital Input. This pin controls the configuration of the switch, as shown in the truth table (see Table 8).
16	A1	Digital Input. This pin controls the configuration of the switch, as shown in the truth table (see Table 8).

TRUTH TABLE

Table 8. Truth Table

A2	A1	A0	EN	Switch Condition
X ¹	X ¹	X ¹	0	None
0	0	0	1	S1
0	0	1	1	S2
0	1	0	1	S3
0	1	1	1	S4
1	0	0	1	S5
1	0	1	1	S6
1	1	0	1	S7
1	1	1	1	S8

¹ X means don't care.

TYPICAL PERFORMANCE CHARACTERISTICS

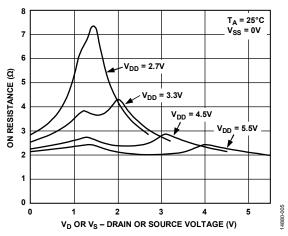


Figure 4. On Resistance as a Function of V_D (V_S) for Single Supply

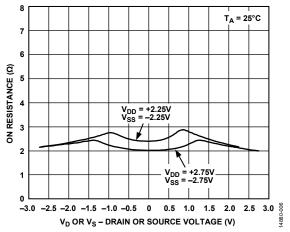


Figure 5. On Resistance as a Function of V_D (V_S) for Dual Supply

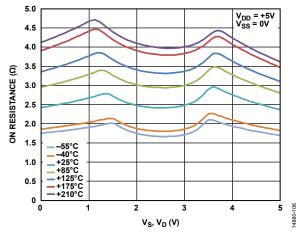


Figure 6. On Resistance as a Function of V_{S_r} V_D for Different Temperatures, 5 V Single Supply

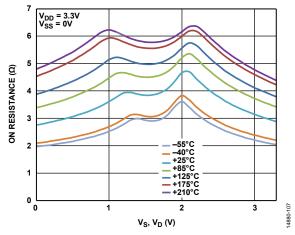


Figure 7. On Resistance as a Function of V_{S} (V_{D}) for Different Temperatures, 3.3 V Single Supply

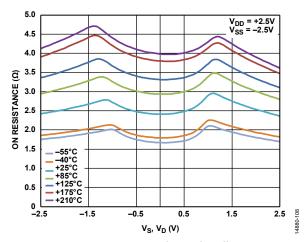


Figure 8. On Resistance as a Function of V_S (V_D) for Different Temperatures, ± 2.5 V Dual Supply

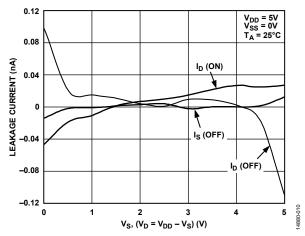


Figure 9. Leakage Current as a Function of V_D (V_s)

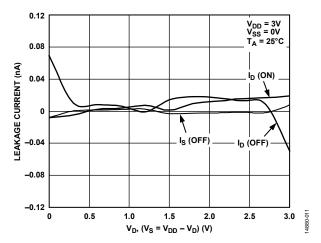


Figure 10. Leakage Current as a Function of V_D (V_S)

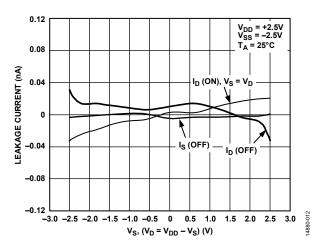


Figure 11. Leakage Current as a Function of V_D (V_S)

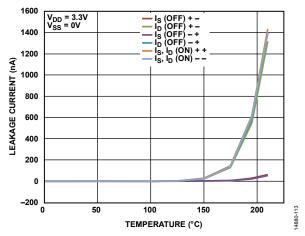


Figure 12. Leakage Current as a Function of Temperature, $V_{DD} = 3.3 \text{ V}$, $V_{SS} = 0 \text{ V}$

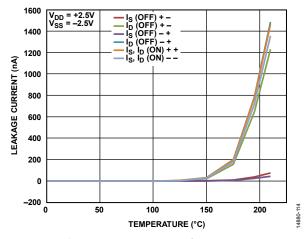


Figure 13. Leakage Current as a Function of Temperature, V_{DD} = +2.5 V, V_{SS} = -2.5 V

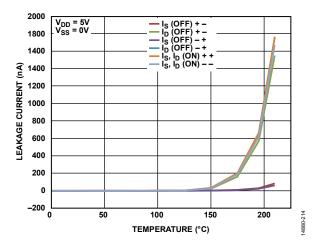


Figure 14. Leakage Current vs. Temperature, $V_{DD} = 5 V$

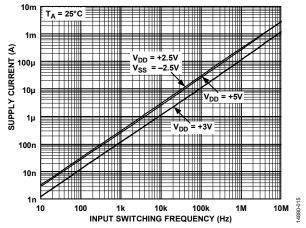


Figure 15. Supply Current vs. Input Switching Frequency

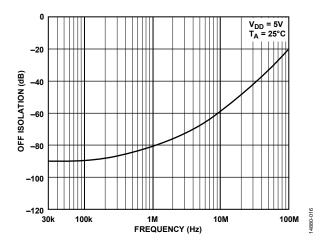


Figure 16. Off Isolation vs. Frequency

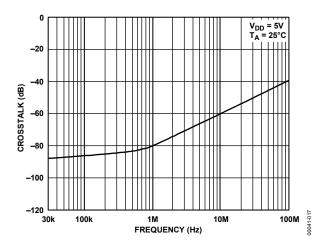


Figure 17. Crosstalk vs. Frequency

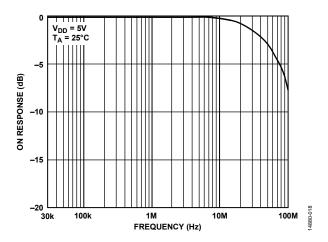


Figure 18. On Response vs. Frequency

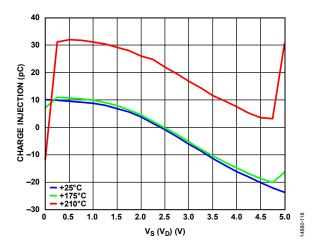


Figure 19. Charge Injection as a Function of V_S (V_D) for Various Temperatures, 5 V Single Supply

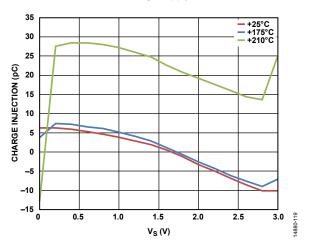


Figure 20. Charge Injection as a Function of V_S (V_D) for Various Temperatures, 3.3 V Single Supply

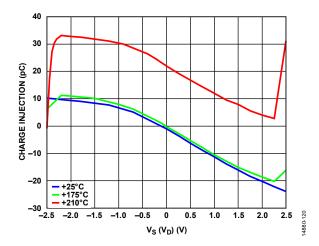


Figure 21. Charge Injection as a Function of V_S (V_D) for Various Temperatures, ± 2.5 V Dual Supply

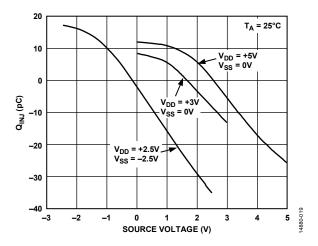


Figure 22. Charge Injection (Q_{INJ}) vs. Source Voltage

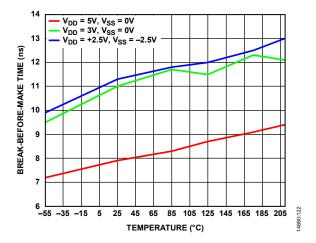


Figure 23. Break-Before-Make Time vs. Temperature

TEST CIRCUITS

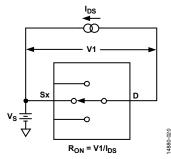
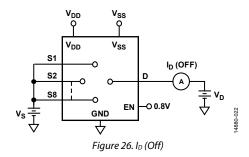


Figure 24. On Resistance



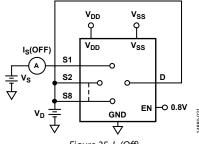
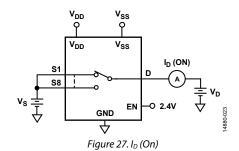
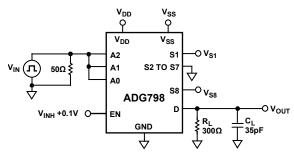


Figure 25. Is (Off)





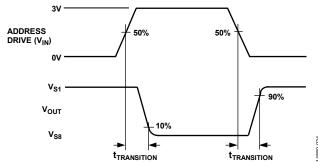
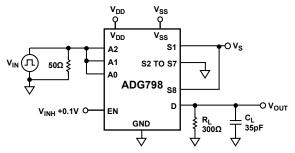


Figure 28. Switching Time of Multiplexer, ttransition



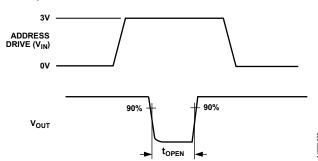


Figure 29. Break-Before-Make Delay, topen

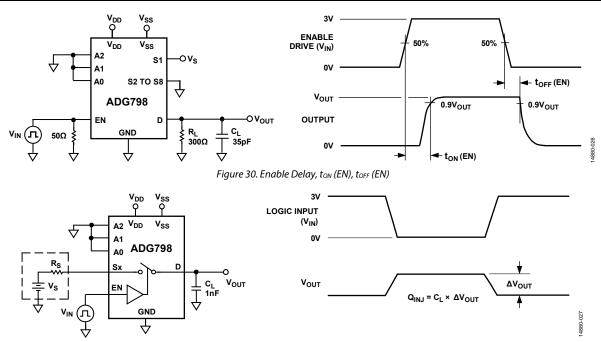


Figure 31. Charge Injection

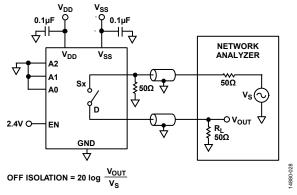


Figure 32. Off Isolation

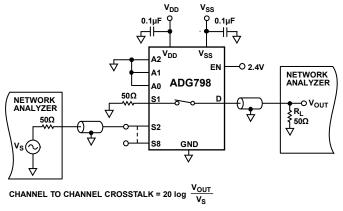
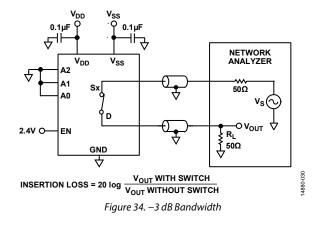


Figure 33. Channel to Channel Crosstalk



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TERMINOLOGY

V_{DD}

V_{DD} is the most positive power supply potential.

\mathbf{v}_{ss}

 V_{SS} is the most negative power supply in a dual-supply application. In single-supply applications, tie V_{SS} to ground at the device.

GND

GND is the ground (0 V) reference.

Sx

Sx are the source terminals and can be inputs or outputs.

D

D is the drain terminal and can be an input or an output.

$\mathbf{A}\mathbf{x}$

Ax is the logic control input.

EN

EN is the active high enable.

RON

Ron is the ohmic resistance between D and Sx.

R_{FLAT (ON)}

 $R_{\rm FLAT\,(ON)}$ flatness is defined as the difference between the maximum and minimum value of on resistance as measured over the specified analog signal range.

Is (Off)

I_S (Off) is the source leakage current with the switch off.

ID (Off)

I_D (Off) is the drain leakage current with the switch off.

In. Is (On)

 I_D , I_S (On) is the channel leakage current with the switch on.

$V_D(V_S)$

 $V_D(V_S)$ is the analog voltage on Terminal D and Terminal Sx.

Cs (Off

Cs (Off) is the off switch source capacitance and is measured with reference to ground.

C_D (Off)

 $C_{\scriptscriptstyle D}\left(Off\right)$ is the off switch drain capacitance and is measured with reference to ground.

C_D , C_S (On)

 C_D , C_S (On) is the on switch capacitance and is measured with reference to ground.

C_{IN}

C_{IN} is the digital input capacitance.

tTRANSITION

ttransition is the delay time measured between the 50% and 90% points of the digital inputs and the switch on condition when switching from one address state to another.

ton (EN)

 $t_{\rm ON}$ (EN) is the delay time between the 50% and 90% points of the EN digital input and the switch on condition.

toff (EN)

 $t_{\rm OFF}$ (EN) is the delay time between the 50% and 90% points of the EN digital input and the switch off condition.

tOPEN

t_{OPEN} is the off time measured between the 80% points of both switches when switching from one address state to another.

Off Isolation

Off isolation is a measure of unwanted signal coupling through an off switch.

Channel to Channel Crosstalk

Channel to channel crosstalk is a measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.

Charge Injection

Charge injection is a measure of the glitch impulse transferred from injection of the digital input to the analog output during switching.

-3 dB Bandwidth

-3 dB bandwidth is the frequency at which the output is attenuated by 3 dB.

On Response

On response is the frequency response of the on switch.

On Loss

On loss is the loss due to the on resistance of the switch.

V_{INI}

 $V_{\text{\tiny INL}}$ is the maximum input voltage for Logic 0.

V_{INH}

 V_{INH} is the minimum input voltage for Logic 1.

$I_{INL}(I_{INH})$

 I_{INL} (I_{INH}) is the input current of the digital input.

I_{DD}

I_{DD} is the positive supply current.

Iss

Iss is the negative supply current.

THEORY OF OPERATION

The ADG798 is a bidirectional, 8:1 CMOS multiplexer designed for very high temperature operation. The device is controlled by four parallel digital inputs (EN, A0, A1, and A2). The EN input allows the ADG798 to be enabled or disabled. When the ADG798 is disabled, the source pins (S1 to S8) disconnect from the drain pin (D). When the ADG798 is enabled, the address lines (A0, A1, and A2) can determine which source pin (S1 to S8) is connected to the drain pin (D).

The low on resistance and on-resistance flatness of this device means that there is minimal signal distortion across the entire signal range of the device. This minimal signal distortion, combined with the close on-resistance match between channels, makes this device ideal for applications where the error due to on resistance is key. The ADG798 also exhibits extremely fast switching times and extremely low power consumption, making the device useful in applications where there is a tight power budget. The ADG798 is compatible with single-supply systems that have a $V_{\rm DD}$ range from 5.5 V to 3.3 V and dual-supply systems at ± 2.5 V.

The ADG798 operates in a wide ambient temperature range from -55°C to +210°C, making the ADG798 perfect for use in harsh environments that subject the device to extreme temperature ranges, such as downhole drilling and avionics.

APPLICATIONS INFORMATION

POWER SUPPLY SEQUENCING

When using CMOS devices, take care to ensure correct power supply sequencing. Incorrect power supply sequencing may result in the device being subjected to stresses beyond the absolute maximum ratings listed in Table 5.

Always apply digital and analog inputs after power supplies and ground. For single-supply operation, tie V_{SS} to GND as close to the device as possible.

OUTLINE DIMENSIONS

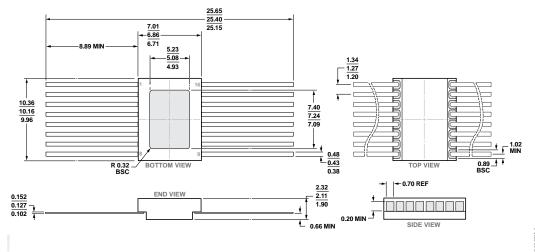


Figure 35. 16-Lead Ceramic Flat Package [FLATPACK] (F-16-1) Dimensions shown in millimeters

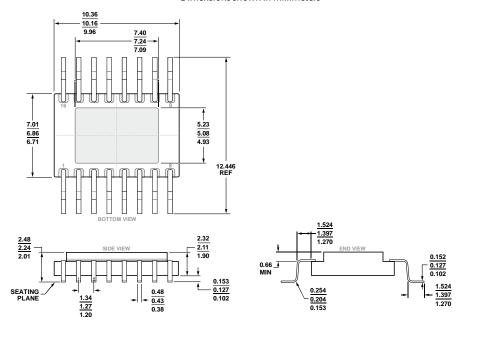


Figure 36. 16-Lead Ceramic Flat Package with Reverse Formed Gullwing Leads [FLATPACK_RF] Cavity Down (FR-16-1)

Dimensions shown in millimetres ORDERING GLUDE

ONDENING GOIDE							
Model ¹	Temperature Range	Package Description	Package Option				
ADG798HFZ	−55°C to +210°C	16-Lead Ceramic Flat Package [FLATPACK]	F-16-1				
ADG798HFRZ	−55°C to +210°C	16-Lead Ceramic Flat Package [FLATPACK_RF]	FR-16-1				
EVAL-ADG798EB1Z		Evaluation Board					

¹ Z = RoHS Compliant Part.

NOTES